

SHORT CIRCUIT TEST SYSTEM 短絡試験器

SCT1010ZZ

1000V
1000A

- SCT1010ZZ has been designed to test energy tolerance of IGBT device at short circuit. Energy amount is calculated by digital oscilloscope waveform which is corresponded with software. Also, it has preventive function not to break D.U.T for safety.
- SCT1010ZZはIGBT素子の短絡時におけるエネルギー耐量を試験します。付属のソフトウェアとの連動によりオシロスコープ波形からエネルギー量を計算します。また安全性を考慮し、D.U.T.の破壊防止機能も盛り込まれています。

MODEL	SCT1010ZZ
MEASURABLE DEVICES	N-IGBT
BIAS SETTING RANGE	
VDD	10V~999V(1V STEP)
ICL	10A~999A(1A STEP)
VGF	0V~+39.9V(0.1V STEP)
VGR	0V~-39.9V(0.1V STEP)
TON	2.0 μ s~999.9 μ s(0.1 μ s STEP)
TEST ITEMS	
OPEN/SHORT	Impress to DUT through 1k Ω at VDD voltage [VDD電圧にて1k Ω を通してDUTへ印加]
BINNING	
BIN INDICATION	PASS, POST-FAIL, FAIL, PRE-FAIL
DIMENSIONS & WEIGHT	
MAIN UNIT	550(W) \times 860+350(D) \times 1700(H)~335kg

Measurement Waveform

